

**Search Notes**

Application/Control No.

10/083,967

Examiner

Edward J. Cain

Applicant(s)/Patent under  
Reexamination

KAMBE

Art Unit

1714

**SEARCHED**

Class	Subclass	Date	Examiner
524	428		
	430		
	432		
	492		
385	15		
	50		
	51		
	131		
	132		
	143		
359	321		
	341.5	6/15/2006	EC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
524	432		
359	341.5		
385	143	6/15/2006	EC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
West: refractive index, spatially or spatial adj2 dependent or dependence, nitride, nanoscale or nanoparticle, dope or doped	6/15/2006	EC